

Title (en)

HIGH SPATIAL RESOLUTION INFRARED ELLIPSOMETER

Title (de)

INFRAROT-ELLIPSOMETER MIT HOHER RÄUMLICHER AUFLÖSUNG

Title (fr)

ELLIPSOMETRE A HAUTE RESOLUTION SPATIALE FONCTIONNANT DANS L'INFRAROUGE

Publication

EP 1301764 A1 20030416 (FR)

Application

EP 01949572 A 20010628

Priority

- FR 0102072 W 20010628
- FR 0009318 A 20000717

Abstract (en)

[origin: WO0206779A2] The invention concerns a spectroscopic ellipsometer comprising: a source (2) capable of emitting a broadband ray (4), a polarizer (10) for polarizing the broadband beam (4), and for producing a polarised incident beam (12) adapted to illuminate a sample (16) according to at least a selected angle; an analyzer (24) for receiving the beam reflected (20) by the illuminated sample (16) and for producing an output beam (28) in response to said reflected beam (20); and at least a reflecting optical element (14) arranged between the source (2) and the sample (16) and/or between the sample (16) and the sensor, and capable of focusing the incident beam (12) and/or the reflected ray (20) according to a selected spot. The ellipsometer further comprises at least a first refracting element (22) arranged between the sample (16) and the sensor and/or between the source (2) and the sample (16) to collect and focus said reflected beam and/or said incident beam, thereby enabling to provide at least a refracting element (22) and a reflecting element (14) on either side of the sample (16) and hence to place the source and the sensor on the same side relative to said spot.

[origin: WO0206779A2] The invention concerns an ellipsometer comprising: a source (2) capable of emitting a broadband ray (4), a polarizer (10) for producing a polarised incident beam (12) adapted to illuminate a sample (16) according to at least a selected angle; an analyzer (24) providing an output beam (28) in response to said reflected beam (20) and at least a reflecting optical element (14) arranged between the source (2) and the sample (16) and/or between the sample (16) and the sensor, and capable of focusing the incident beam (12) and/or the reflected beam (20) according to a selected spot. The ellipsometer further comprises at least a first refracting optical element (22) arranged between the sample (16) and the sensor and/or between the source (2) and the sample (16) to collect and focus said reflected beam and/or said incident beam, thereby enabling to provide at least a refracting element (22) and a reflecting element (14) on either side of the sample (16) and hence to place the source and the sensor on the same side relative to said spot.

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Citation (search report)

See references of WO 0206780A1

Citation (examination)

US 5859424 A 19990112 - NORTON ADAM E [US], et al

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DOCDB simple family (publication)

WO 0206779 A2 20020124; **WO 0206779 A3 20020328**; AU 7070101 A 20020130; AU 7645601 A 20020130; EP 1301763 A2 20030416; EP 1301764 A1 20030416; FR 2811761 A1 20020118; FR 2811761 B1 20021011; JP 2004504590 A 20040212; JP 2004504591 A 20040212; KR 100846474 B1 20080717; KR 20030022292 A 20030315; KR 20030026322 A 20030331; US 2004027571 A1 20040212; US 2004070760 A1 20040415; US 6819423 B2 20041116; US 7230701 B2 20070612; WO 0206780 A1 20020124

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